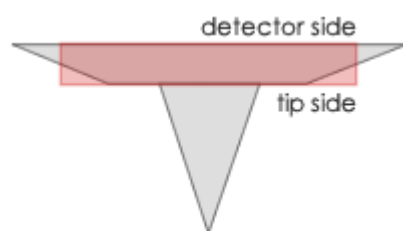


Cantilever Data	Value	Range*
Resonance Frequency	25 kHz	10 - 39 kHz
Force Constant	0.2 N/m	0.02 - 0.7 N/m
Length	225 μm	220 - 230 μm
Mean Width	48 μm	42.5 - 52.5 μm
Thickness	1 μm	0.5 - 1.5 μm

NanoWorld® Pointprobe® CONTSC AFM probe is an alternative AFM cantilever type for contact mode applications. The length of AFM cantilever is reduced with respect to the preferred contact mode type enabling easier exchange with non-contact mode probes for some AFM instruments. Additionally, this AFM probe type allows the application for lateral or friction force mode.

All SPM and AFM probes of the Pointprobe® series are made from monolithic silicon which is highly doped to dissipate static charge. They are chemically inert and offer a high mechanical Q-factor for high sensitivity. The AFM tip is shaped like a polygon based pyramid with a typical height of 10 - 15 μm .

Additionally, this AFM probes offers typical AFM tip radius of curvature of less than 8 nm.



A trapezoidal cross section of the AFM cantilever and therefore 30% wider (e.g. NCH) AFM cantilever detector side result in easier and faster laser adjustment. Additionally, because there is simply more space to place and reflect the laser beam, a higher SUM signal is reached.

Tip shape: Standard

Coating: none

Order Code	Quantity	Data Sheet
CONTSC-10	10	yes
CONTSC-20	20	yes
CONTSC-50	50	no
CONTSC-W	380	yes